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L5	L4 and (first adj direction)	42	L5
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L3	L2 and magnetoresistance	422	L3
L2	L1 and (magnetization with (vector\$1 or direction\$1))	821	L2
L1	(pinned adj layers) and magnetic	1302	L1

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pinned and layers and direction

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1 Hysteresis and interaction between the magnetic layers in spin valves

Nioshioka, K.; Gangopadhyay, S.; Fujiwara, H.; Parker, M.;
Magnetism, IEEE Transactions on, Volume: 31 Issue: 6, Nov. 1995
Page(s): 3949 -3951

[\[Abstract\]](#) [\[PDF Full-Text \(308 KB\)\]](#) **IEEE JNL**

2 Highly field-sensitive transverse-biased non-hysteretic spin valves

Fujiwara, H.; Chun-Hong Hou; Nishioka, K.;
Magnetism, IEEE Transactions on, Volume: 32 Issue: 5, Sept. 1996
Page(s): 4603 -4605

[\[Abstract\]](#) [\[PDF Full-Text \(256 KB\)\]](#) **IEEE JNL**

3 Characterization of magnetic stability in spin valve test devices

Hardner, H.T.;
Magnetism, IEEE Transactions on, Volume: 36 Issue: 5, Sept 2000
Page(s): 2584 -2586

[\[Abstract\]](#) [\[PDF Full-Text \(60 KB\)\]](#) **IEEE JNL**

4 Critical current hysteresis in low angle Y-Ba-Cu-O bicrystals

Grimaldi, G.; Boffa, V.; Celentano, G.; Fabbri, F.; Gambardella, U.;
Pace, S.; Petrisor, T.;

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GMR and integrated

[Search Again](#)**Results:**Journal or Magazine = **JNL** Conference = **CNF** Standard = **STD****1 Thermally stable, low saturation field, low hysteresis, high GMR CoFe/Cu multilayers***Wang, D.; Anderson, J.; Daughton, J.M.;*

Magnetics, IEEE Transactions on , Volume: 33 Issue: 5 , Sept. 1997

Page(s): 3520 -3522

[\[Abstract\]](#) [\[PDF Full-Text \(276 KB\)\]](#) **IEEE JNL****2 High sensitivity magnetic field sensor using GMR materials with integrated electronics***Brown, J.L.;*

Circuits and Systems, 1995. ISCAS '95., 1995 IEEE International Symposium on , Volume: 3 , 28 April-3 May 1995

Page(s): 1864 -1867 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(480 KB\)\]](#) **IEEE CNF****3 Integrated GMR isolation technique***Black, W.C., Jr.; Hermann, T.H.; Hui, S.;*

Circuits and Systems, 1996., IEEE 39th Midwest symposium on , Volume: 1 , 18-21 Aug. 1996

Page(s): 127 -130 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(380 KB\)\]](#) **IEEE CNF****4 Wafer charging in process equipment and its relationship to GMR heads charging damage**